Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/669,347	NAKANO, TAKAHIKO
Examiner	Art Unit
Sang Nguyen	2877

SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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(INCLUDING SEA	RCH STRATEGY	<u>) </u>
	DATE	EXMR
EAST	6/2/2005	SN
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